FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

392.1893 TEA 10/826322 FIRST NAMED INVENTOR Michiya INOUE, et al.

APPLICATION NO.

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

FILING DATE GROUP ART UNIT
April 19, 2004 TBA 2193

ATTORNEY DOCKET NO.

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	АВ						
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSL YES	NO NO
/J.W./	AG	05-313708	11/26/93	Japan			abs	
/J.W./	AH	2002- 358102	12/13/02	Japan			abs	
	Al							
	AJ							
	AK							
	AL							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

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EXAMINER	J Jue Wang/	DATE CONSIDERED 09/25/2007	<u> </u>	<u> </u>

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Sheet 1 of 1

392.1893

FIRST NAMED INVENTOR

10/826,322

INFORMATION DISCLOSURE STATEMENT Michiya INOUE, et al.

FILING DATE

GROUP ART UNIT

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April 19, 2004

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*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
/J.W./	AA	6,810,433	10-2004	Nishimaki et al.			
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	AL					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) TRANSLATION YES NO /J.W./ AM Notification of Grounds for Rejection (Office Action) in corresponding Japanese Patent Application 115753/2003

EXAMINER	DATE CONSIDERED				
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